CLAIMS

Having described the invention, what is claimed as new and desired to be secured by Letters Patent is:

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- 1. A system for determining the presence or absence of an ion in a plasma, comprising: an ion source having a plasma chamber sized and dimensioned for generating a plasma having an ion present therein, and
 - a probe assembly coupled to the ion source for detecting said ions of said plasma.

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- 2. The system of claim 1, wherein said probe assembly comprises a probe device extending within the plasma chamber for extracting said ion from said plasma.
- 3. The system of claim 2, wherein the probe device comprises:

a probe body having a conical tip disposed within the plasma chamber, and a focusing element mounted to said probe body and adapted for generating a field, when energized, therein.

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- 4. The system of claim 1, wherein the probe assembly comprises:

 a probe device for extracting one or more of said ions from said plasma, and
 a filter coupled to said probe device for filtering said one ore more ions extracted
 by said probe device from said plasma.
- 5. The system of claim 4, wherein the filter comprises at least one of a Wien filter and an EXB filter.
 - 6. The system of claim 4, wherein the filter comprises a plurality of steel strips for concentrating a magnetic field within the filter.
- 7. The system of claim 6, wherein the plurality of steel strips are biased at different voltages to produce one of a potential gradient and a uniform electric field within a passageway.

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- 8. The system of claim 4, further comprising means for generating an electric field within the filter to separate one or more ions based on ion velocity.
- 9. The system of claim 1, further comprising a vacuum source coupled to said probe device for creating a selected pressure condition therein for facilitating extraction of said ion from said plasma chamber.
- 10. The system of claim 1, wherein said probe assembly comprises a probe device
 having a probe body, a portion of which is adapted to extend into said plasma chamber,
 and a set of electrodes coupled to said probe body for creating a field therein.
 - 11. The system of claim 1, wherein said probe assembly comprises a probe device for extracting one or more ions from said plasma, a filter for filtering said ions, and a controller for detecting said one or more ions.
 - 12. A probe assembly suitable for use with an ion source for detecting an ion in a plasma within a plasma chamber of the ion source, comprising:
 - a probe body adapted for extending at least partly within the plasma chamber of the ion source;
 - a focusing element coupled to said probe for generating a selected field within the probe; and
 - a filter coupled to said probe for filtering said ion passing through said probe and extracted from said plasma chamber.
 - 13. The probe assembly of claim 12, wherein said probe body comprises a passageway sized and dimensioned for allowing the ion to pass therethrough, said body having a conical end portion that extends within the plasma chamber.
- 30 14. The probe assembly of claim 12, wherein a set of electrodes is coupled to said probe body for creating a field therein.

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- 15. The probe assembly of claim 14, wherein said electrodes comprise a quadrupole focusing element for generating a field within the probe body for said ion from said plasma chamber.
- 5 16. The probe assembly of claim 12, wherein said filter comprises an EXB filter.
 - 17. A method for detecting an ion within a plasma generated within a plasma chamber of an ion source, comprising the steps of:

extracting the ion from the ion source with a probe device; and detecting the ion extracted from the plasma chamber.

- 18. The method of claim 17, further comprising the step of, prior to the detecting step, filtering one or more ions extracted from the ion source.
- 15 19. The method of claim 17, wherein the step of filter comprises the step varying a field so as to filter the one or more ions based on ion velocity.
 - 20. The method of claim 17, further comprising the step of twisting a set of electrodes to produce a rotating quadrupole field that alternately focuses ions in all directions.